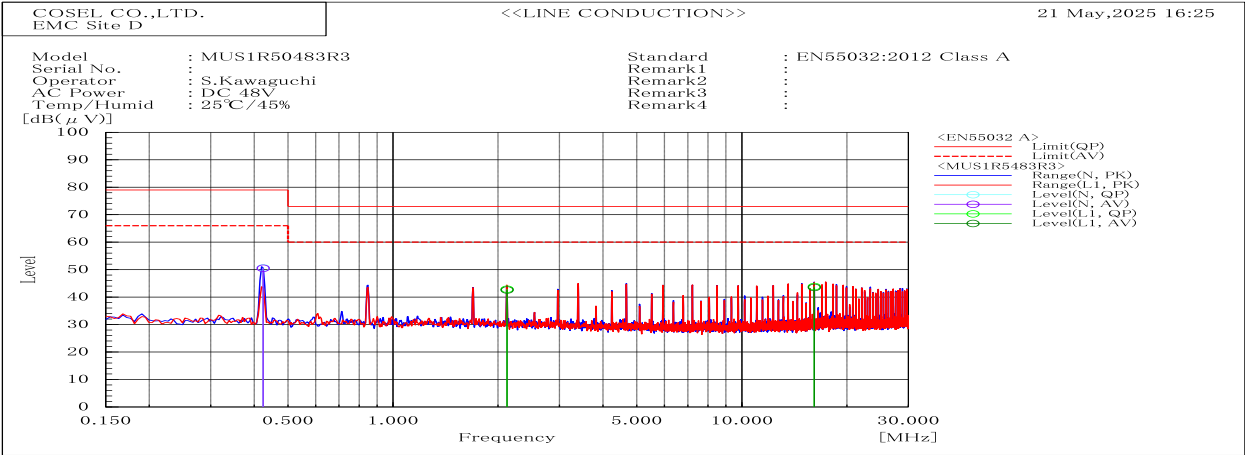
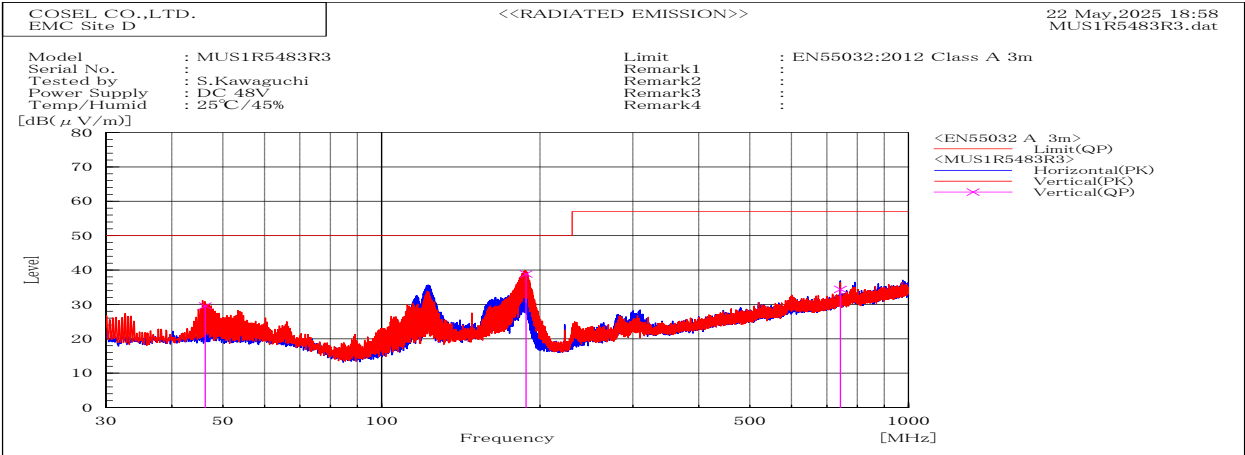


DATA SHEET		Date	22-May-25
Model	MUS1R5483R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



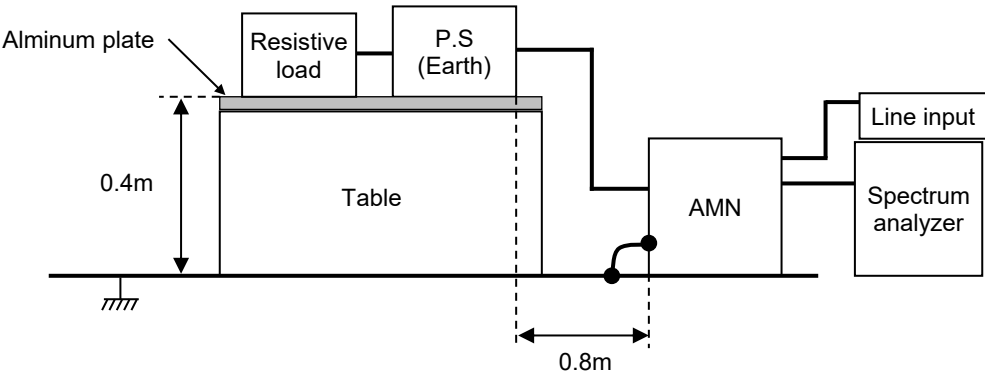
Frequency MHz	Line	Level		Limit		Margin		Pass/Fail	Remark
		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
2.123	L1	42.9	42.6	73	60	30.1	17.4	Pass	
16.13	L1	43.8	43.5	73	60	29.2	16.5	Pass	
0.424	N	50.6	50.5	79	66	28.4	15.5	Pass	



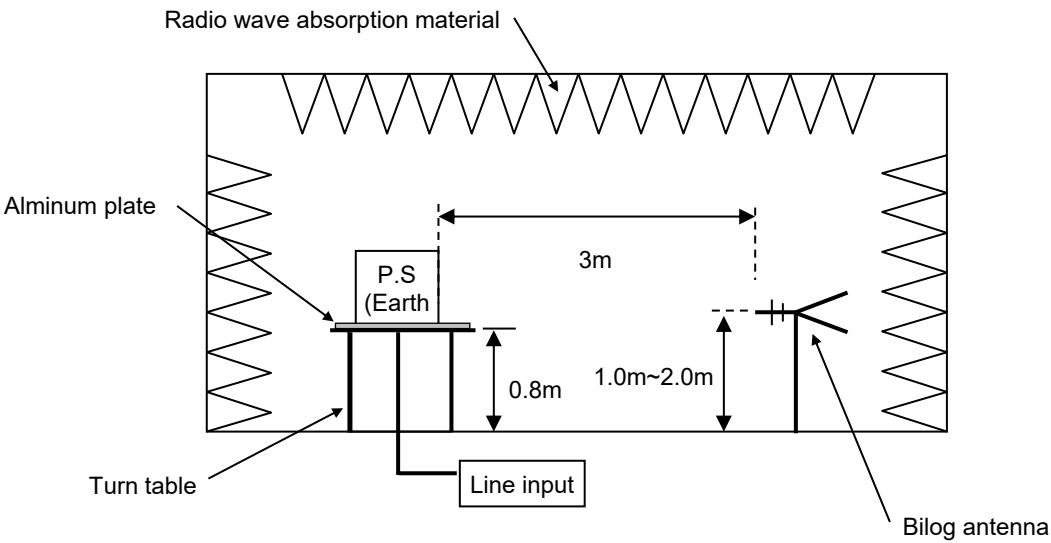
Frequency MHz	Polarization	Stability	Level		Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(uV/m)		dB(uV/m)	dB				
			QP		QP	QP				
188.031	V	Stable	38.8		50	11.2	Pass	102	35.3	
46.282	V	Stable	29.6		50	20.4	Pass	100.2	299.7	
742.547	V	Stable	34.4		57	22.6	Pass	188.2	182.7	

DATA SHEET		Date	22-May-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission

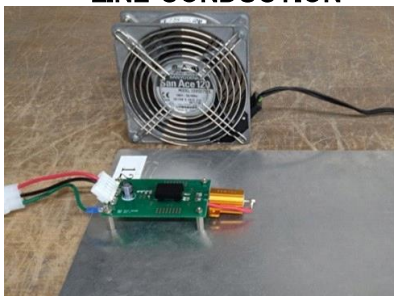


Conditions

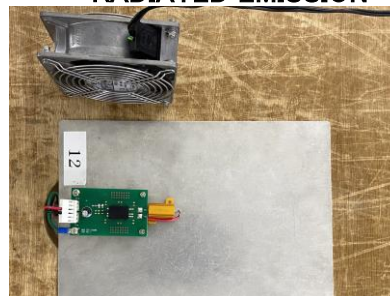
Test : EMI
Model Name: MUS1R5□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

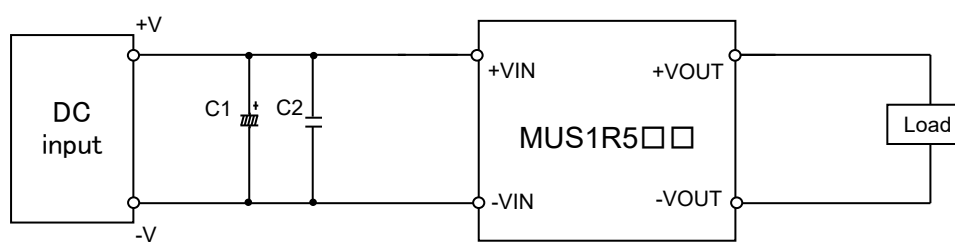


Fig.1 MUS1R505□, MUS1R512□, MUS1R524□ Testing circuitry

- | | | | |
|------|-----------|-----------------|---|
| C1 : | MUS1R505□ | 16V 220 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUS1R512□ | 50V 100 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUS1R524□ | - | |
| C2 : | MUS1R505□ | 16V 22 μ F | Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING) |
| | MUS1R512□ | 25V 22 μ F | Ceramic capacitor (C3216JB1E226MT TDK) |
| | MUS1R524□ | 50V 10 μ F | Ceramic capacitor (C3216X7R1H106KT TDK) |

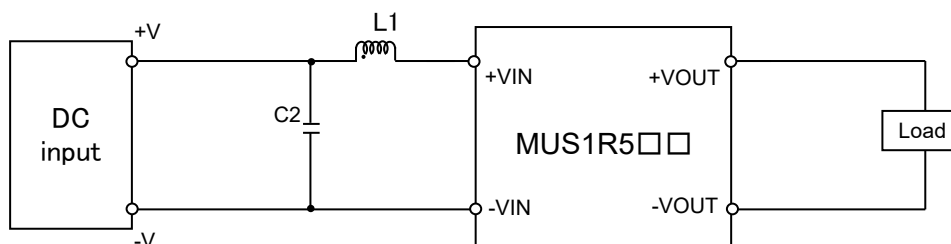


Fig.2 MUS1R548□ Testing circuitry

- | | | | |
|------|-----------|------------------|--|
| C2 : | MUS1R548□ | 100V 2.2 μ F | Ceramic capacitor (C3216X7S2A225KT TDK) |
| L1 : | MUS1R548□ | 520mA 15 μ H | Inductor (LQH32PN150MN0L MURATA MANUFACTURING) |